

Search Notes

Application/Control No.

10/724,172

Examiner

TUYEN T. NGUYEN

Applicant(s)/Patent under
Reexamination

TAKEYAMA ET AL.

Art Unit

2832

SEARCHED

Class	Subclass	Date	Examiner
336	90-96, 107, 192, 198	5/13/2005	TTN
123	634-635	5/13/2005	TTN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR